

Search Notes

Application/Control No.

10/705,818

Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

NAKAYAMA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	6/19/2007	CH
455	411	6/19/2007	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	6/19/2007	CH
Combined Text Searched	6/19/2007	CH
Reviewed Prior Arts	6/19/07	CH